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(12) **United States Design Patent** (10) **Patent No.:** **US D804,435 S**
Taniguchi et al. (45) **Date of Patent:** **** Dec. 5, 2017**

(54) **FLAP IN AN ADHESIVE TAPE FOR SEMICONDUCTOR MANUFACTURING**

CPC H01L 21/563; H01L 21/6836; H01L 23/3157; H01L 24/81; C09J 163/00
See application file for complete search history.

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(56) **References Cited**

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U.S. PATENT DOCUMENTS

D194,932 S * 4/1963 Masuda D7/585
D228,439 S * 9/1973 Mercadante D7/585
D258,019 S * 1/1981 Baronet D5/7

(Continued)

FOREIGN PATENT DOCUMENTS

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JP D1315621 11/2007

(**) Term: **14 Years**

OTHER PUBLICATIONS

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Related U.S. Application Data

(60) Continuation of application No. 29/413,518, filed on Feb. 16, 2012, now abandoned, which is a division of application No. 29/389,787, filed on Apr. 15, 2011, now Pat. No. Des. 656,910.

(57) **CLAIM**

The ornamental design for a flap in an adhesive tape for semiconductor manufacturing, as shown and described.

(30) **Foreign Application Priority Data**

Oct. 15, 2010 (JP) D2010-024764

(51) **LOC (10) Cl.** **13-03**

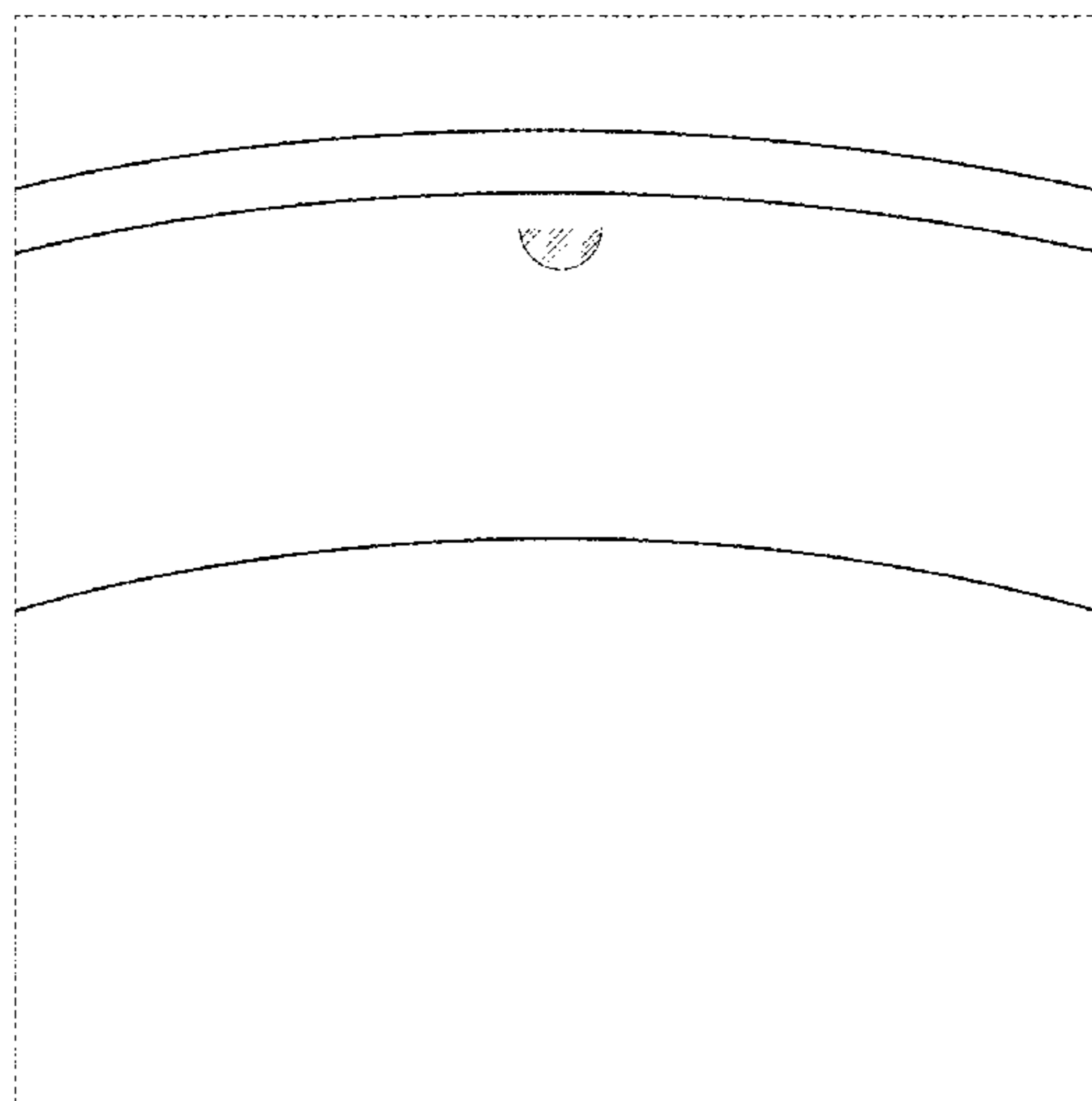
(52) **U.S. Cl.**
USPC **D13/180**

(58) **Field of Classification Search**
USPC D10/71, 75; D19/69; D24/189;
D13/182; 33/494, 758, 562, 759;
101/288; 206/390; 40/638, 641; 428/43,
428/343, 345, 353, 114, 455; D7/585;
D20/22, 42

DESCRIPTION

FIG. 1 is a top plan view of a flap in an adhesive tape for semiconductor manufacturing incorporating our new design; FIG. 2 is a bottom plan view of the flap of FIG. 1; FIG. 3 is a cross-sectional view taken at line 3-3 in FIG. 1; FIG. 4 is an enlarged view of portion 4-4, 4-4 in FIG. 1; and, FIG. 5 is a perspective view of the flap in use. The broken lines are included for the purpose of illustrating environmental structure and form no part of the claimed design.

1 Claim, 5 Drawing Sheets



(56)

References Cited

U.S. PATENT DOCUMENTS

D287,683 S *	1/1987	Unger	D20/11	D492,354 S	6/2004	Fujii	
5,624,033 A *	4/1997	Arai	B65D 5/542	D493,838 S	8/2004	Fujii	
				206/461	6,864,295 B2 *	3/2005	Mitarai B29C 65/76
D392,330 S *	3/1998	Sucese	D20/42				428/345
D395,641 S *	6/1998	Gaete	D14/447	D529,096 S *	9/2006	Jordan D20/11
5,771,524 A *	6/1998	Woods	A45D 40/00	D544,607 S *	6/2007	Henry D24/189
				15/209.1	D549,189 S *	8/2007	Misumi D13/182
6,464,815 B1 *	10/2002	Beaudry	A45D 29/11	D589,473 S *	3/2009	Takamoto D13/182
				15/208	D621,051 S *	8/2010	Kase D24/189
6,493,898 B1 *	12/2002	Woods	B05C 17/00	D621,803 S *	8/2010	Maruyama D13/182
				15/209.1	D628,170 S *	11/2010	Maruyama D13/182
D480,811 S *	10/2003	Horhota	D24/189	D656,909 S *	4/2012	Taniguchi D13/182
D490,470 S	5/2004	Fujii			D656,910 S *	4/2012	Taniguchi D13/182
D490,854 S	6/2004	Fujii			D664,511 S *	7/2012	Taniguchi D13/182
D490,855 S	6/2004	Fujii			D664,512 S *	7/2012	Taniguchi D13/182
D491,226 S	6/2004	Fujii			D680,505 S *	4/2013	Taniguchi D13/182
D491,227 S	6/2004	Fujii			D689,831 S *	9/2013	Taniguchi D13/180
D491,228 S	6/2004	Fujii			D690,278 S *	9/2013	Taniguchi D13/180
D491,229 S	6/2004	Fujii			9,076,832 B2 *	7/2015	Taniguchi H01L 21/568
					2007/0241436 A1	10/2007	Ookubo et al.	
					2010/0080989 A1	4/2010	Asai et al.	

* cited by examiner

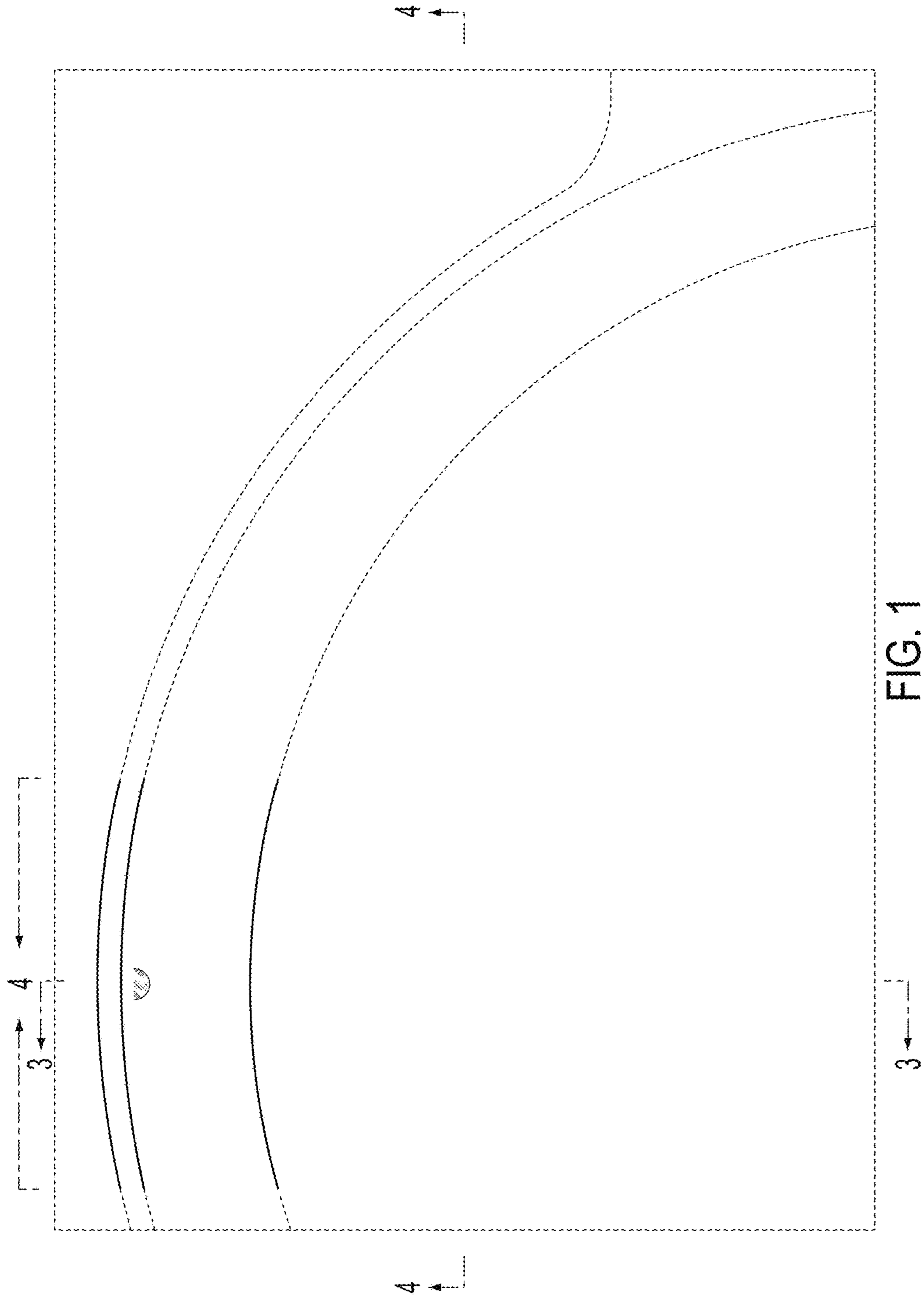


FIG. 1

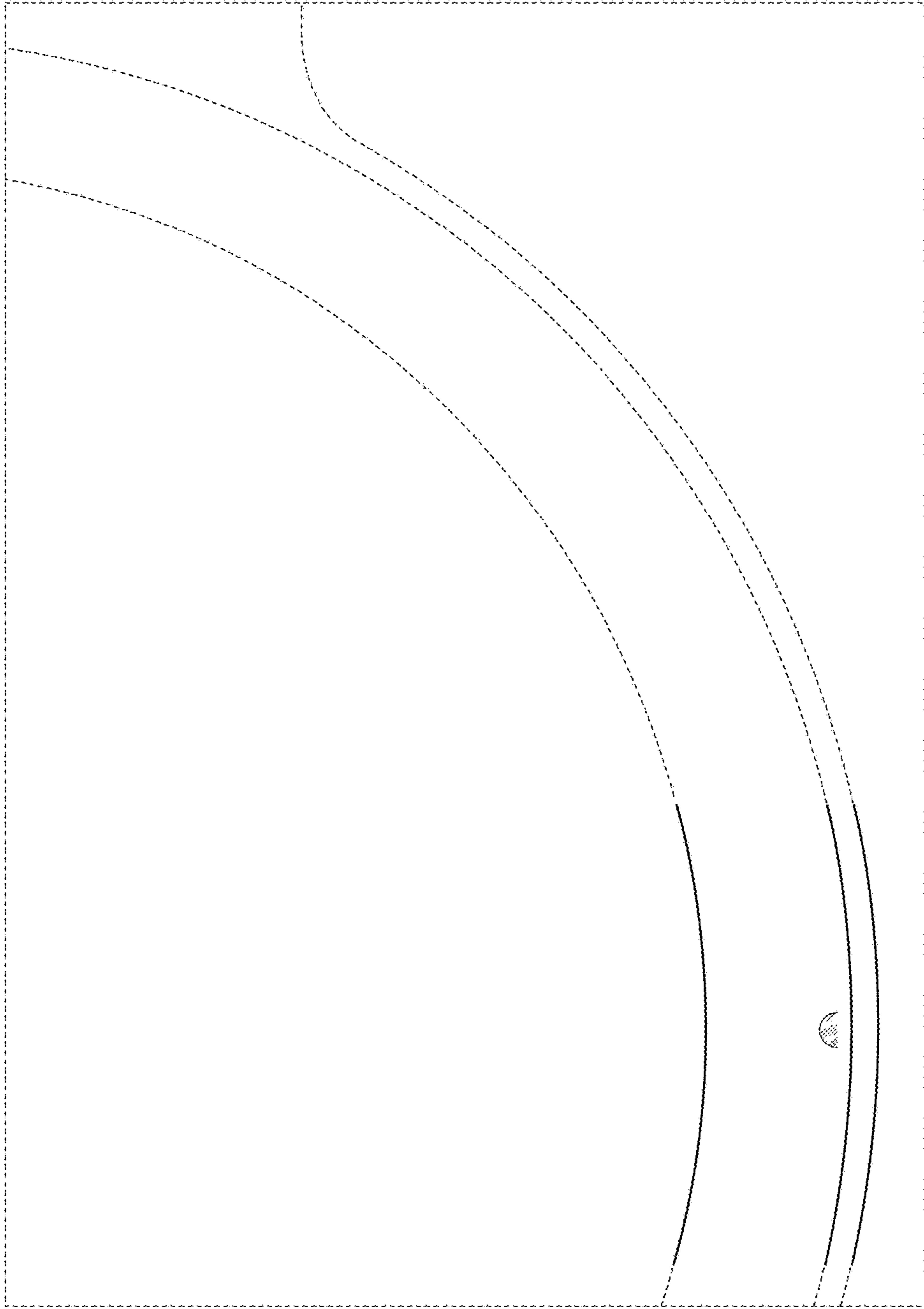


FIG. 2

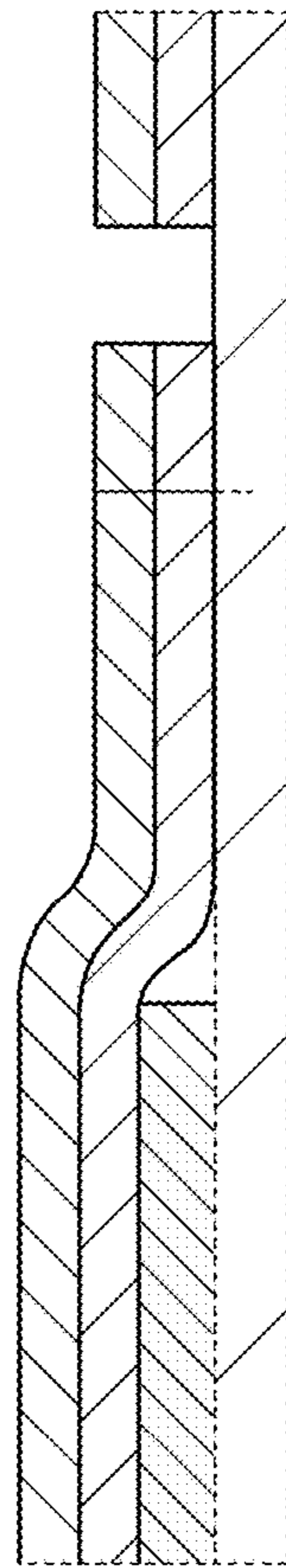


FIG. 3

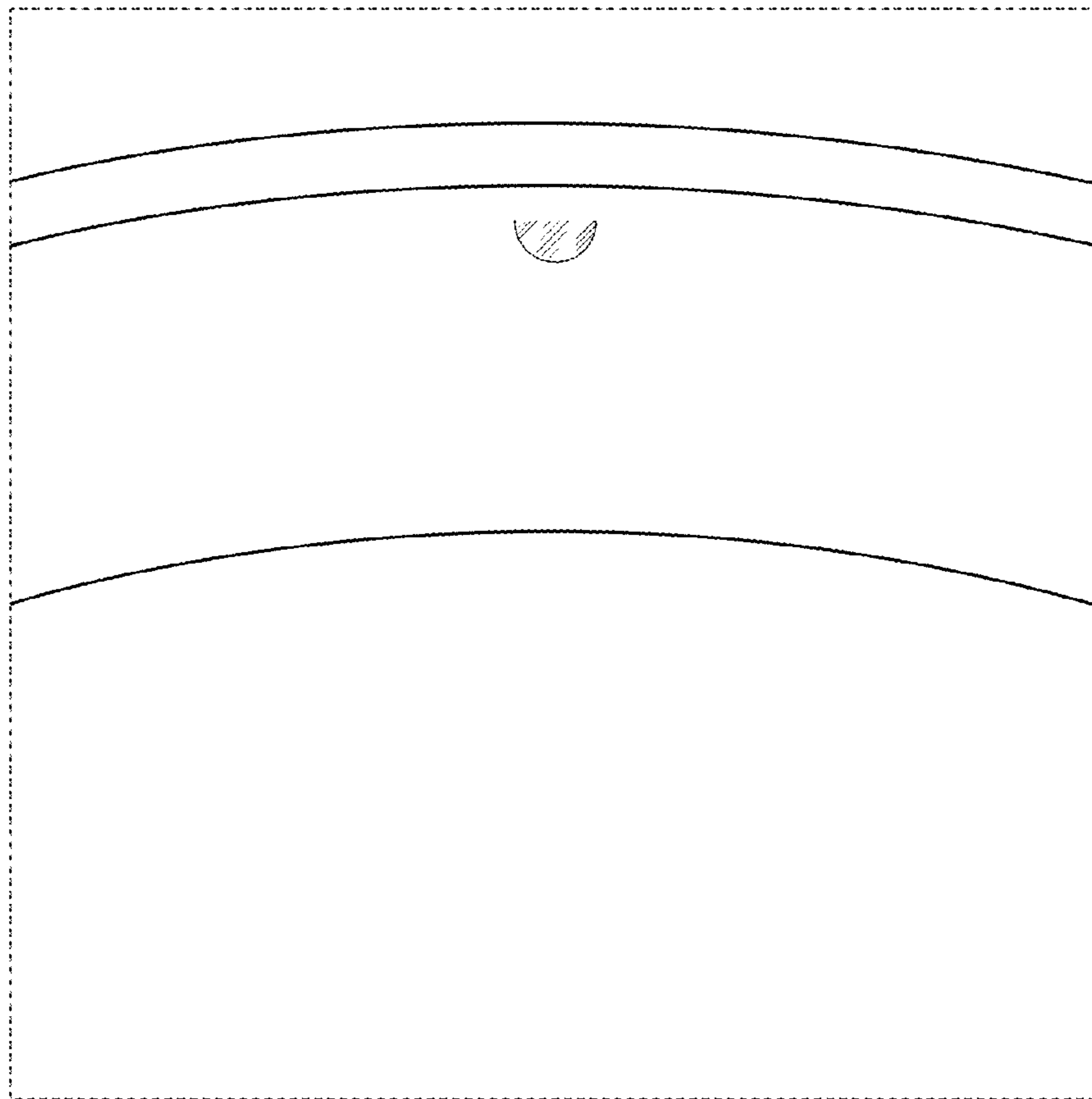


FIG. 4

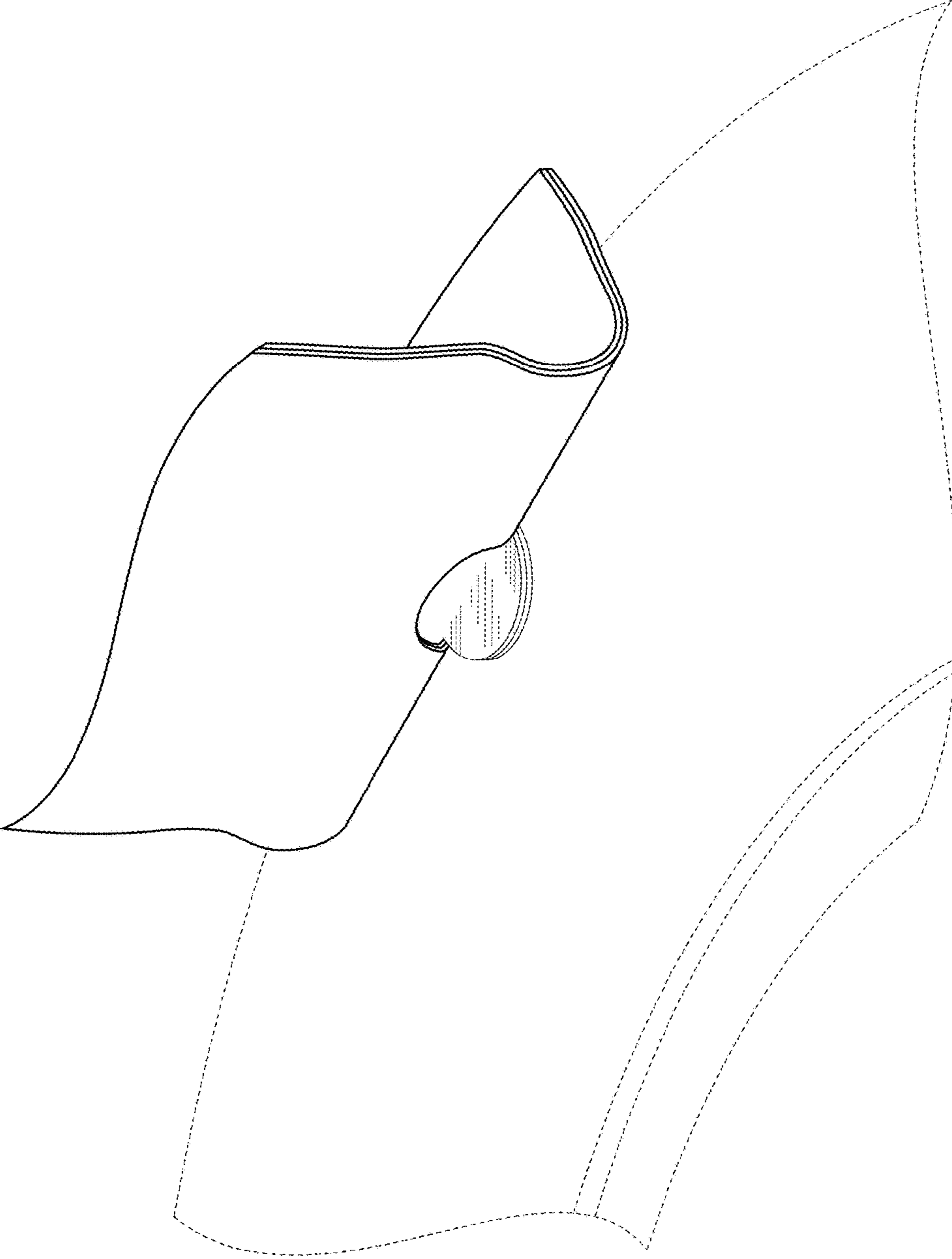


FIG. 5